

WIDE BANDGAP RELIABILITY TESTING

Independent High-Power Device and Design Testing

OUR CAPABILITIES

GROUP NIRE'S WIDE BANDGAP RELIABILITY TESTING FACILITY is an independent testing facility that can perform reliability analyses of WBG semiconductor devices, with several tests & services. Alongside our Wide Bandgap Testing Facility, our Research and Development Center can create custom tests for devices, modules, prototype designs or product designs.



OUR SERVICES:

- Complement gaps in the client's testing capabilities.
- Provide independent testing services to verify or corroborate the client's test results
- Aid clients in determining the suitability of devices for specific applications.

GENERAL TESTING PARAMETERS: (Our parameters are constantly improving)

- Up to 15kV
- Low Voltage continuous current up to 300 A
- Humidity from 30% to 90%
- Temperature range of -68° C to 200° C
- 1 kA pulsed current

† Temperature dependent

powered by



LIST OF INDIVIDUAL TESTS AND CAPABILITIES

HTRB

Our High Temperature Reverse Bias test can accommodate up to 6 kV devices and can be run up to 200° C for as long as desired.

HTGB

Our High Temperature Gate Bias test can accommodate a Gate bias of up to +/-70 V and can be run up to 200° C for as long as desired.

TDDB

Our Time Dependent Dielectric Breakdown test can accommodate Gate bias of up to +/-70 V and can be run for as long as desired.

DV/DT

Our dv/dt test can accommodate DUTs rated between 600 V and 1.6 kV, at a dv/dt rate adjustable up to 300 V/ns or greater.

STANDARD PRICING

POWERAMERICA MEMBER PRICING

HTRB, HTGB, OR TDDB (pricing per device)

	1 DEVICE	12 DEVICES		1 DEVICE	12 DEVICES
Base Cost	\$5023	\$628	Base Cost	\$4521	\$566
Every 100 Hours	\$2489	\$312	Every 100 Hours	\$2240	\$281

Pricing listed is for 1 or 12 devices. We price on a sliding scale and can offer custom quotes on any amount of devices that you need tested.

DV/DT (pricing per device)

	1 DEVICE	10 DEVICES		1 DEVICE	10 DEVICES
Base Cost	\$8493	\$8068	Base Cost	\$7644	\$7262
Per Data Point	\$525	\$499	Per Data Point	\$473	\$450

Pricing listed is for 1 or 10 devices. We price on a sliding scale and can offer custom quotes on any amount of devices that you need tested.

CUSTOM

Our custom testing can accommodate voltages up to 15kV and currents up to 300 A for any of our offered tests (where applicable). Custom test stands can also be developed for different device, module, or design testing.

CONSULTING

Our R&D team combines experience from many realms of electrical engineering including but not limited to Power Electronics and would like to provide you with consulting services to help you with your next project.

FOR MORE INFORMATION:

GROUP NIRE

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